

---

## Latent Damage and Reliability in Semiconductor Devices

**Advisor:** Dr. Randall Geiger

**Client:** Dr. Randall Geiger, EcpE

**Members (roles):**

Sean Santella (Leader)

Jaehyuk Han (Webmaster)

Hayle Olson (Communication Leader)

David Ackerman (Key Concept Holder)

---

**Weekly Summary:**

This week we met with our team and experimented with the electric fencer that we purchased locally. We also worked on soldering some components to help with stressing the devices.

**Meeting Notes:**

Team Meeting (Oct. 28<sup>th</sup> at 5PM)

*Duration:* 1 Hour

*Members Present:* Sean Santella, Jaehyuk Han, Hayle Olson, David Ackerman

*Notes:* This team meeting was held in the TLA in Coover to troubleshoot and experiment our electric fencer. We were able to find it's output voltage and also what amount of resistance we'll need to step down the voltage.

**Weekly Accomplishments:**

We purchased an electric fencer locally. We also started soldering an r-string that will be used on/with the stress PCB.

**Plans for Next Week:**

- Completely integrate the electric fencer with our stress PCB
- Stress a device with our electric fencer/stress PCB

**Pending Issues:**

- We do not have access to the 3<sup>rd</sup> floor VLSI lab still Dr. Mina is looking into this for us.

### **Individual Contributions:**

Sean Santella: Attended lecture and weekly team meeting, purchased electric fencer, PCB and part soldering.

Jaehyuk Han: Attended lecture and weekly team meeting.

Hayle Olson: Attended lecture and weekly team meeting, purchased electric fencer, PCB and part soldering, and wrote weekly report.

David Ackerman: Attended lecture and weekly team meeting.

### **Hourly Contributions:**

<u>Member:</u>	<u>Weekly Hours:</u>	<u>Total Hours:</u>
Sean Santella	3.5	31.0
Jaehyuk Han	2.0	25.0
Hayle Olson	4.0	29.0
David Ackerman	2.0	26.5